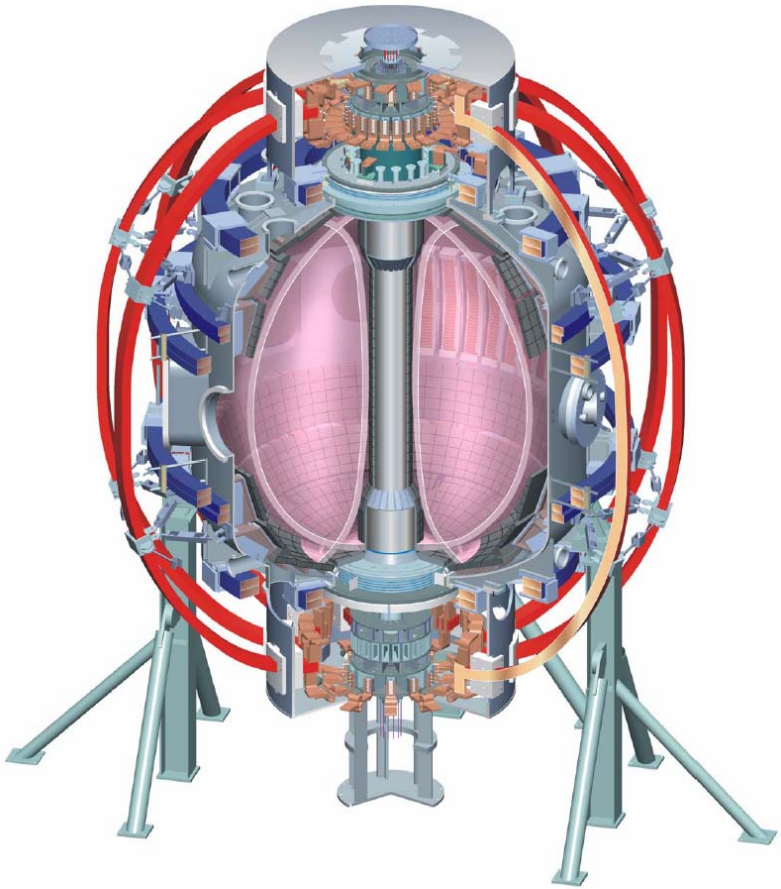
Dependence of B_T on high-k fluctuations



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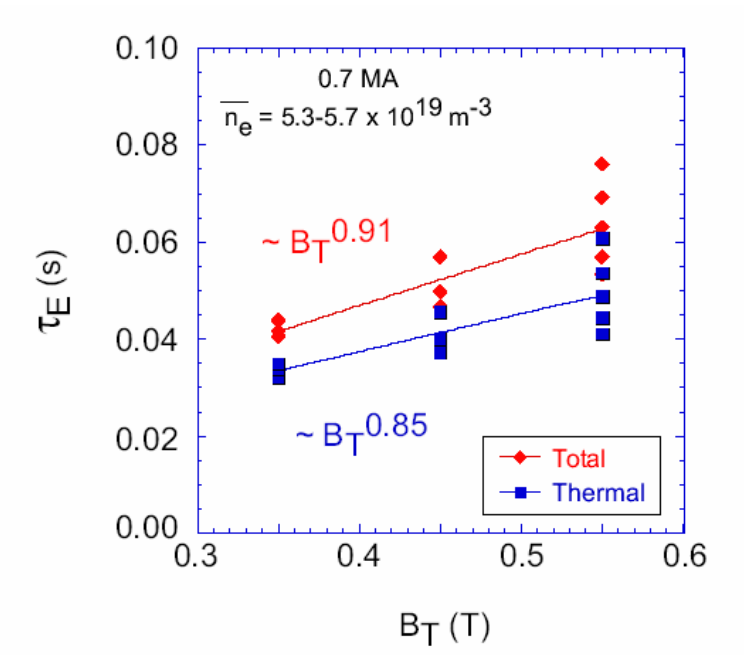
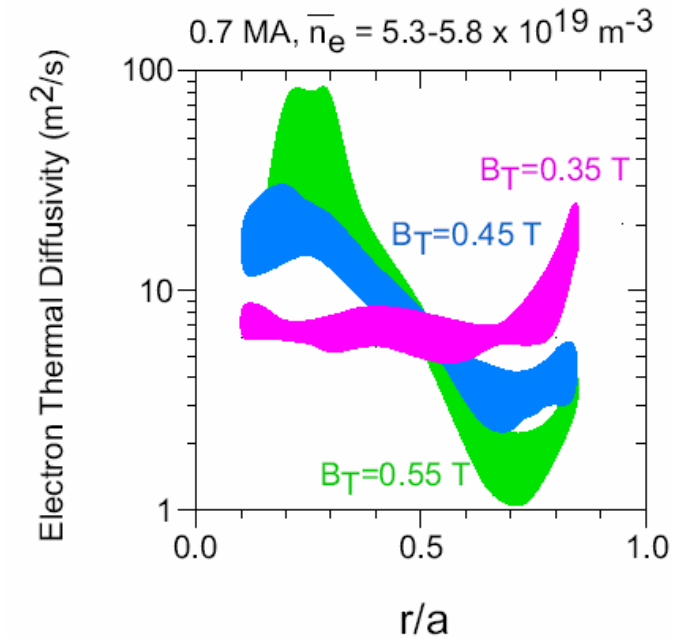
XP Review
February 7, 2007

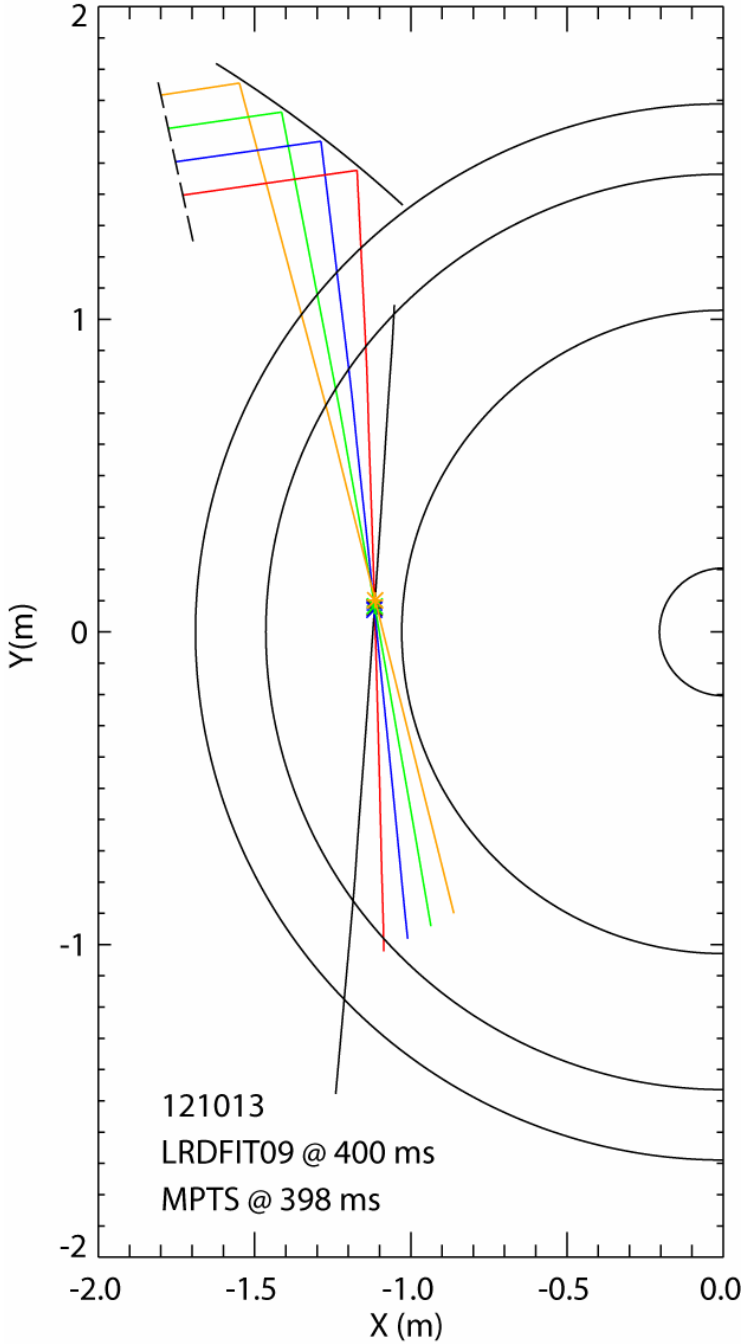
Follow-up to XP532 (Kaye)

- B_T scan at 0.7 MA, 4 MW NBI, comparable density profiles
- Electron transport responsible for improved confinement with B_T
- τ_E exhibits B_T dependence stronger than y98,2





High-k configuration for measurement at r/a = 0.25



Shot Matrix

- Measure high-k fluctuations inside, outside, and at χ_e inversion location

	r/a ~ 0.25	r/a ~ 0.5	r/a ~ 0.7
3.5 kG (121014)			
4.5 kG (121013)			
5.5 kG (121012)			

2 controlled accesses required to reconfigure high-k system